



Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/057,026	CHEN ET AL.	
	Examiner	Art Unit	
	Ly T. TRAN	2853	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
347	48			347	63	65				
INTERNATIONAL CLASSIFICATION										
B	4	1	J	2/14						
				/						
				/						
				/						
				/						
<i>Lyleana</i> 5/22/05 (Assistant Examiner) (Date)				 STEPHEN MEIER SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date)				Total Claims Allowed: 10		
<i>JUKOW</i> 9/30/05 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	O.G. Print Fig. 1H	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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